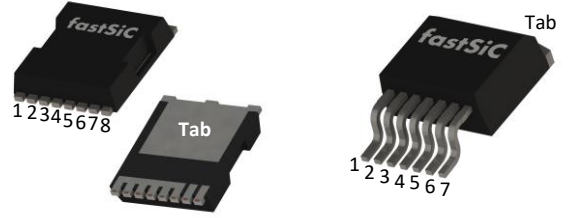
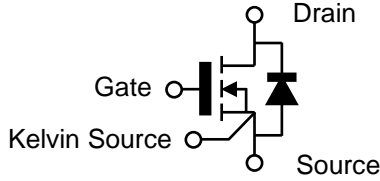


**Silicon Carbide MOSFET**  
650V, 30mΩ SiC MOSFET – Falcon Series



**Product Information:**



**TOLL**

**TO-263-7L**

**Features**

- Optimized  $R_{DS(on)}$  with Rapid Switching Behavior
- Compatible with Standard Gate Drivers
- Clean Kelvin-Source Switching Pin-out
- High Avalanche Endurance Capability
- Optimized for High Power Density Applications
- RoHS Compliant and Halogen Free
- Validated Based on AEC-Q101 Automotive Qualified

Terminal	Packaging Type	
	TOLL	TO-263-7L
Gate	1	1
Drain	Tab	Tab
Source	3, 4, 5, 6, 7, 8	3, 4, 5, 6, 7
Kelvin Source	2	2

**Benefits**

- Higher System Efficiency
- Increase Parallel Device Convenience
- Enable High Temperature Application
- Allow High Frequency Operation
- Realize Compact and Lightweight Systems
- High Reliability

**Potential Applications**

- Switching Mode Power Supply
- PFC & DC/DC Converter
- EV Charging Station
- UPS
- Renewable Energy
- Power Inverter & Motor Driver

**Key Performance Parameters**

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS @ T_{j(max)}}$	700	V
Recommended Gate-Source Turn-On Voltage	$V_{GS}$	15~18	
Drain-Source On-State Resistance	$R_{DS(on)}$	30	mΩ
Continuous Drain Current	$I_D$	74	A
Pulse Drain Current	$I_{D, pulse}$	191	
Power Dissipation	$P_{tot}$	268	W
Avalanche Energy	$E_{AS}$	1100	mJ
Gate Charge	$Q_G$	125	nC
Output Capacitive Charge	$Q_{oss}$	102	
Junction & Storage Temperature	$T_j, T_{stg}$	-55 to 175	°C

Part Number	Package	Marking
FF06030FA	TOLL	FF06030A
FF06030J-7A	TO-263-7L	FF06030A
--	--	--

For further information about comparable products, please contact ([www.fastsic.com](http://www.fastsic.com)).

**Maximum Ratings: ( $T_j = 25^\circ\text{C}$ , unless otherwise specified)**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Voltage	$V_{DSS}$	650	--	--	V	$V_{GS}=0\text{V}, I_D=100\mu\text{A}$
Continuous Drain Current	$I_D$	--	--	74 53	A	$V_{GS}=18\text{V}, T_C=25^\circ\text{C}$ $V_{GS}=18\text{V}, T_C=100^\circ\text{C}$
Pulse Drain Current	$I_{D,pulse}$	--	--	191		Per Fig. 13
Continuous Body Diode Current	$I_S$	--	--	49		$V_{GS}=0\text{V}, T_C=25^\circ\text{C}$
Avalanche Energy, Single Pulse	$E_{AS}$	--	--	1100	mJ	$L=25\text{mH}$
Operate Gate Source Voltage	$V_{GS,op}$	-8~0	--	15~18	V	Recommended operating values
Transient Gate Source Voltage	$V_{GS,tran.}$	-10	--	22		Transient operating limit (AC $f > 1\text{Hz}$ , pulse width $< 100\text{ns}$ )
Power Dissipation	$P_{tot}$	--	--	268	W	$T_C=25^\circ\text{C}$
Junction Temperature	$T_j$	-55	--	175	°C	--
Storage Temperature	$T_{stg}$	-55	--	175		
Soldering Temperature	$T_L$	--	--	260		

**Electrical Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>DC Characteristics (at <math>T_j = 25^\circ\text{C}</math>, unless otherwise specified)</b>						
Drain-source Breakdown Voltage	$V_{(BR)DSS}$	650 --	-- 700	-- --	V	$V_{GS}=0\text{V}, I_D=100\mu\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}, I_D=100\mu\text{A}, T_j=175^\circ\text{C}$
Drain-Source On-State Resistance	$R_{DS(on)}$	-- --	30 43	45 --	mΩ	$V_{GS}=18\text{V}, I_D=30\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=18\text{V}, I_D=30\text{A}, T_j=175^\circ\text{C}$
Gate-Source Threshold Voltage	$V_{th}$	--	2.5	--	V	$V_{GS}=V_{DS}, I_D=40\text{mA}$
Zero Gate Voltage Drain Current	$I_{DSS}$	--	2	60	μA	$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_j=25^\circ\text{C}$
Gate-Source Leakage Current	$I_{GSS}$	--	--	100	nA	$V_{GS}=18\text{V}, V_{DS}=0\text{V}$
Body Diode Forward Voltage	$V_{SD}$	-- --	3.3 2.9	-- --	V	$V_{GS}=0\text{V}, I_S=20\text{A}, T_j=25^\circ\text{C}$ $V_{GS}=0\text{V}, I_S=20\text{A}, T_j=175^\circ\text{C}$
<b>AC Characteristics (at <math>T_j = 25^\circ\text{C}</math>, unless otherwise specified)</b>						
Input Capacitance	$C_{iss}$	--	3015	--	pF	$V_{DS}=400\text{V}, V_{GS}=0\text{V},$ $f=250\text{kHz}, V_{AC}=25\text{mV}$
Output Capacitance	$C_{oss}$	--	199	--		
Reverse Capacitance	$C_{rss}$	--	26	--		
Effective Output Capacitance, energy related	$C_{o(er)}^1$	--	222	--		
Effective Output Capacitance, time related	$C_{o(tr)}^2$	--	279	--		
$C_{oss}$ Stored Energy	$E_{oss}$	--	15	--		
Output Capacitive Charge	$Q_{oss}$	--	102	--	nC	
Internal Gate Resistance	$R_{G,int.}$	--	2.4	--	Ω	$f=1\text{MHz}, V_{AC}=25\text{mV}$

<sup>1</sup>  $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400V.

<sup>2</sup>  $C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400V.

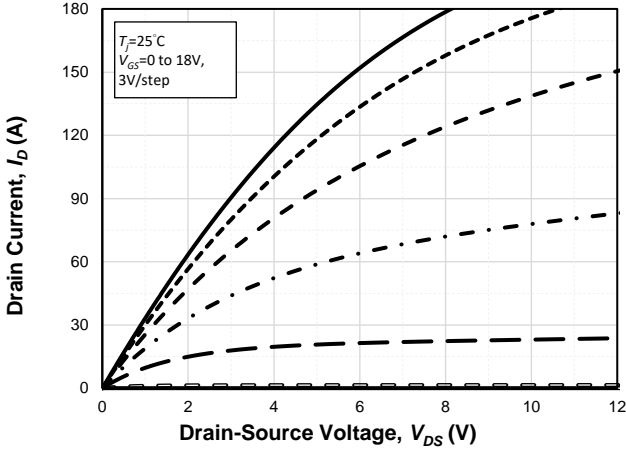
**Switching Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
<b>Gate Characteristics</b>						
Gate to Source Charge	$Q_{GS}$	--	15	--	nC	$V_{DS}=400V, V_{GS}=0V/15V, I_D=40A$
Gate to Drain Charge	$Q_{GD}$	--	72	--		
Total Gate Charge	$Q_G$	--	125	--		
<b>Inductive Load</b>						
Turn On Delay Time	$t_{d(on)}$	--	57	--	ns	$V_{DS}=400V,$ $I_D=28.5A,$ $V_{GS}=-3/+15V,$ $R_{G(ext.)}=2.7\Omega$ External SiC Diode as an FWD
Rise Time	$t_r$	--	47	--		
Turn Off Delay Time	$t_{d(off)}$	--	14	--		
Fall Time	$t_f$	--	35	--		
Turn On Switching Energy	$E_{on}$	--	324	--	$\mu J$	External SiC Diode as an FWD
Turn Off Switching Energy	$E_{off}$	--	54	--		
<b>Resistive Load</b>						
Turn On Delay Time	$t_{d(on)}$	--	18	--	ns	$V_{DS}=400V,$ $I_D=26.7A, V_{GS}=-3/+15V,$ $R_{G_{on, ext.}}=2.7\Omega, R_{G_{off, ext.}}=1\Omega$ $R_L=15\Omega$
Rise Time	$t_r$	--	25	--		
Turn Off Delay Time	$t_{d(off)}$	--	38	--		
Fall Time	$t_f$	--	14	--		
<b>Body Diode Characteristics</b>						
Reverse Recovery Charge	$Q_{rr}$	--	128	--	nC	$V_{GS}=0V,$ $I_S=40A, V_{DS}=400V,$ $di/dt=300A/\mu s$ * $Q_{rr}$ herein excluded the $Q_{oss}$ value.
Reverse Recovery Time	$t_{rr}$	--	68	--	ns	
Peak Reverse Recovery Current	$I_{rrm}$	--	3.5	--	A	

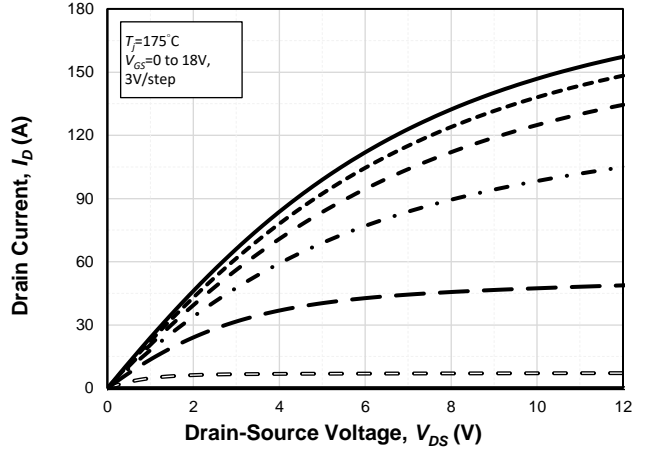
**Thermal Characteristics:**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Thermal Impedance, junction-case	$R_{th-jc}$	--	0.56	--	K/W	--
Thermal Impedance, junction-ambient	$R_{th-ja}$	--	40	--		Device on PCB, with 6 cm <sup>2</sup> of cooling area

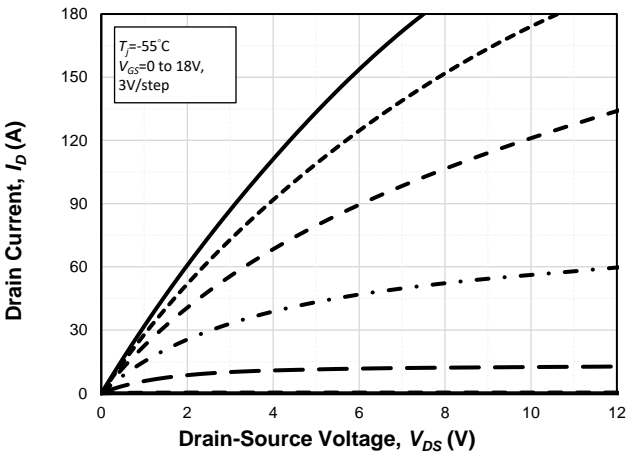
**Electrical Characteristics Diagrams**



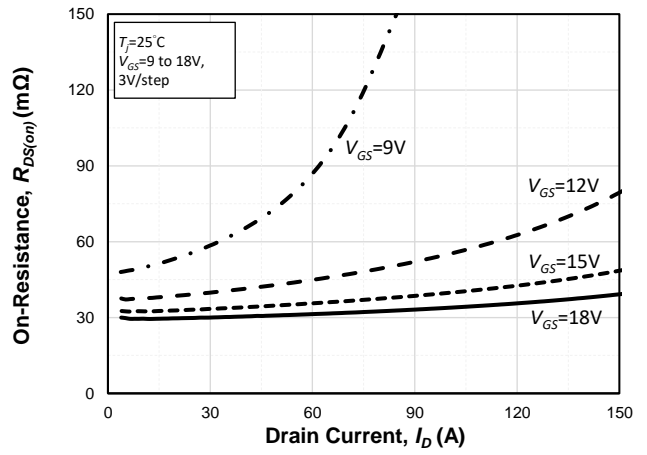
**Fig. 1 Typical Output Characteristics at  $T_j=25^\circ\text{C}$**



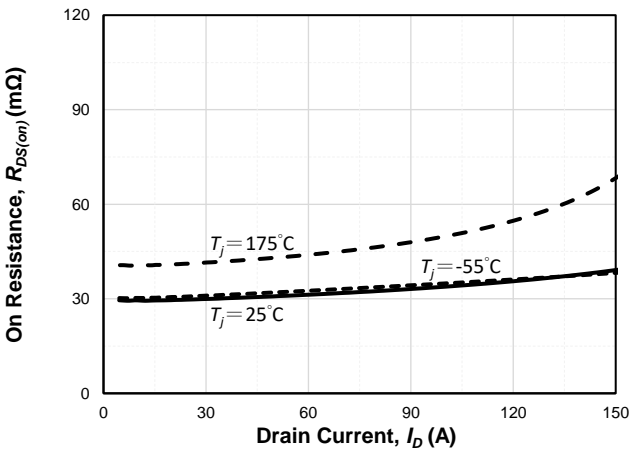
**Fig. 2 Typical Output Characteristics at  $T_j=175^\circ\text{C}$**



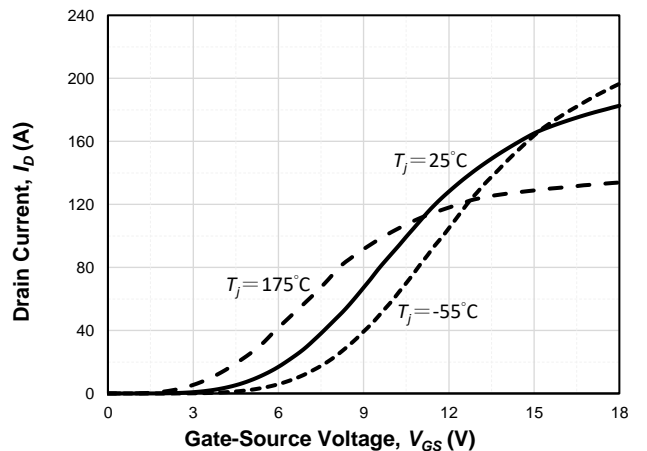
**Fig. 3 Typical Output Characteristics at  $T_j=-55^\circ\text{C}$**



**Fig. 4 Typ.  $R_{DS(on)}$  vs.  $I_D$  with Various  $V_{GS}$**

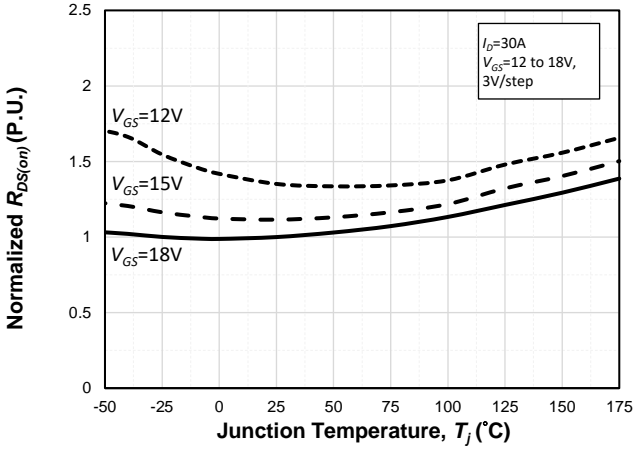


**Fig. 5 Typ.  $R_{DS(on)}$  vs.  $I_D$  with Various  $T_j$ ,  $V_{GS}=18\text{V}$**

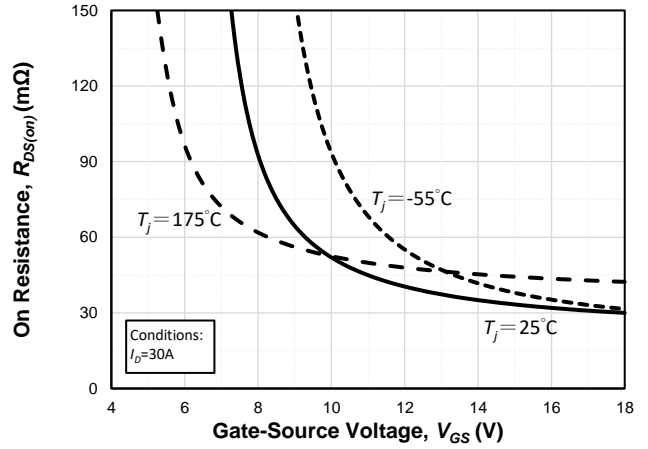


**Fig. 6 Typ.  $I_D$  vs.  $V_{GS}$  with Various  $T_j$ ,  $V_{DS}=10\text{V}$**

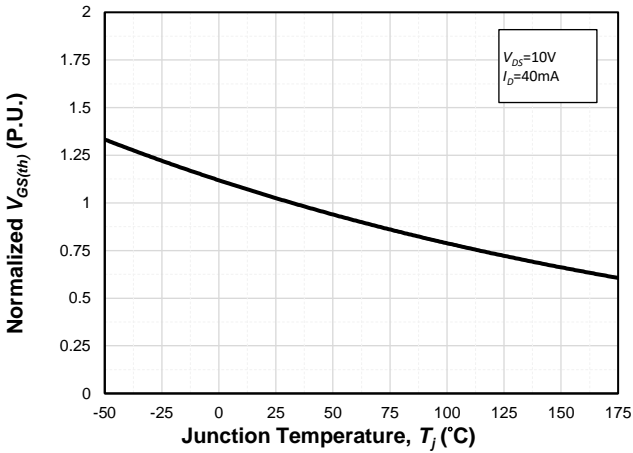
**Electrical Characteristics Diagrams**



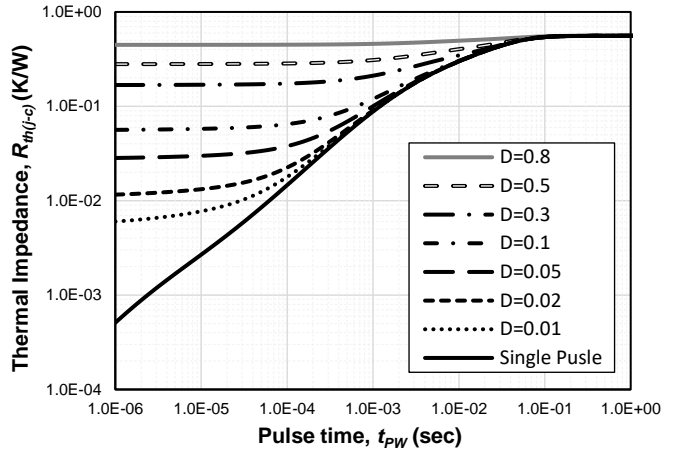
**Fig. 7 Normalized  $R_{DS(on)}$  vs.  $T_j$  with Various  $V_{GS}$**



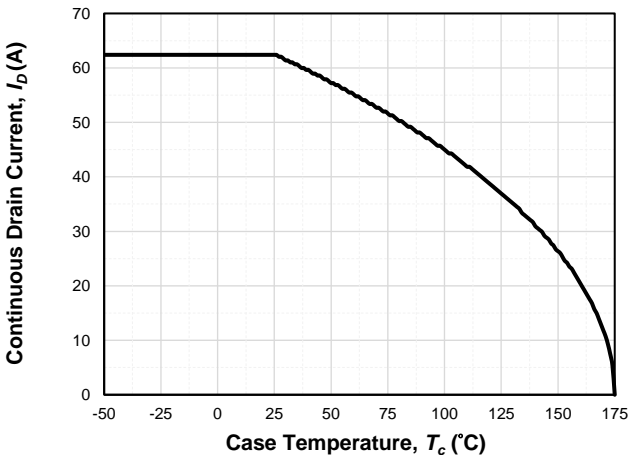
**Fig. 8 Typ.  $R_{DS(on)}$  vs.  $V_{GS}$  with Various  $T_j$**



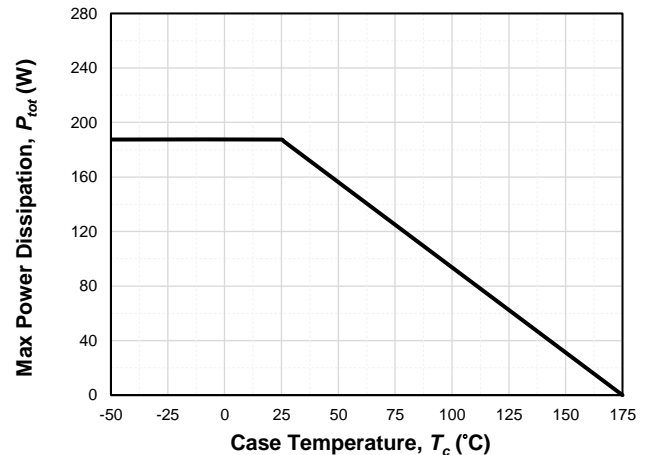
**Fig. 9 Normalized  $V_{th}$  vs.  $T_j$**



**Fig. 10 Typ. Transient Thermal Impedance  $R_{th-jc}$**

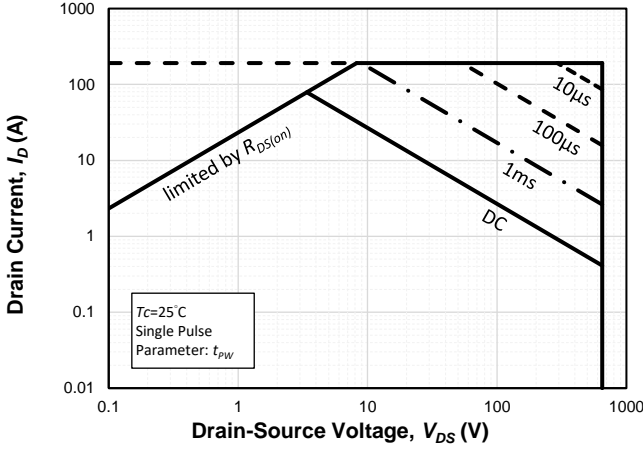


**Fig. 11 Continuous  $I_D$  De-rating at  $V_{GS}=18V$ ,  $T_j \leq 175^\circ C$**

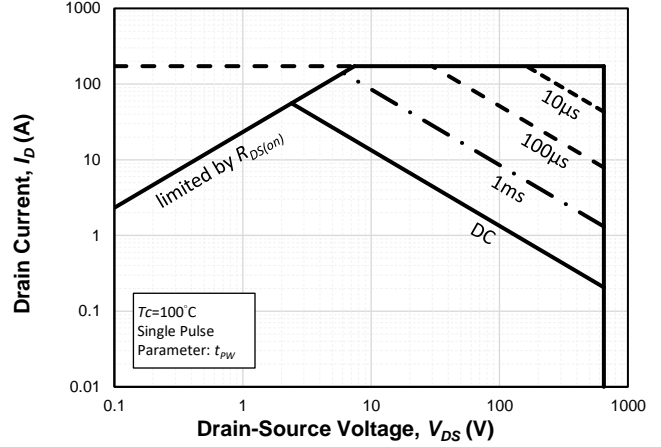


**Fig. 12 Power Dissipation at  $V_{GS}=18V$ ,  $T_j \leq 175^\circ C$**

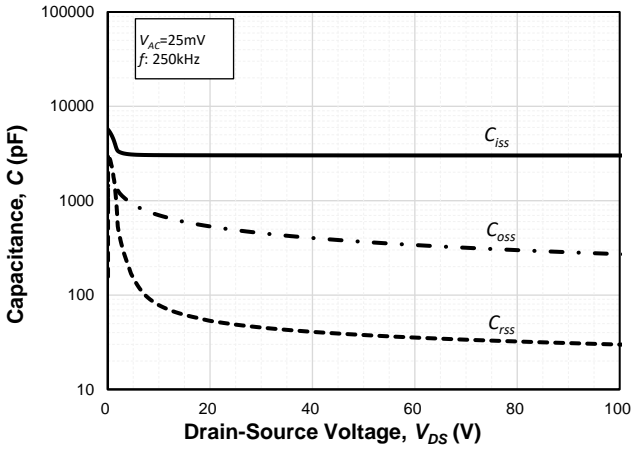
**Electrical Characteristics Diagrams**



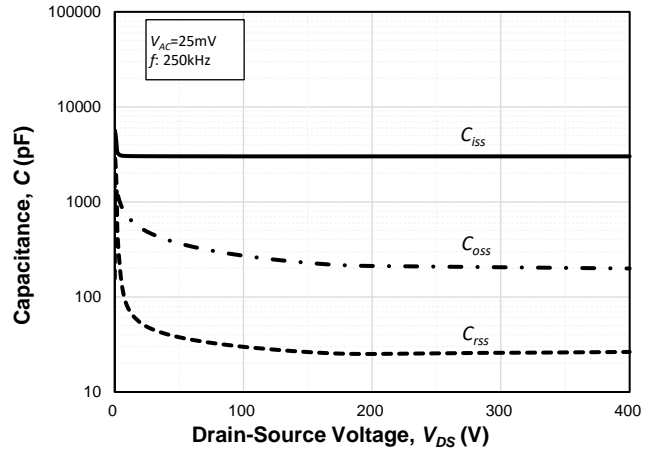
**Fig. 13 Safe Operating Area at  $T_c=25^\circ\text{C}$**



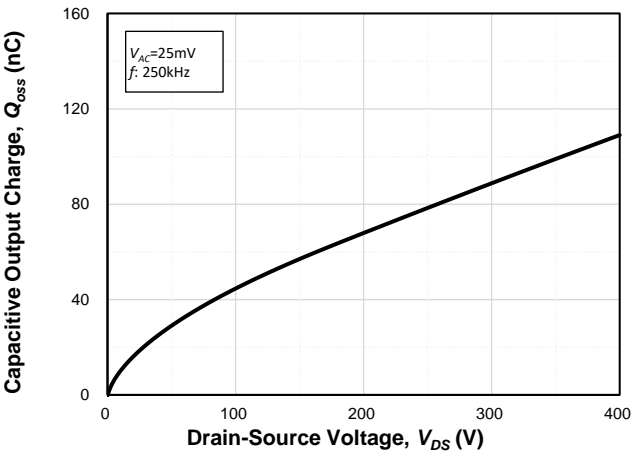
**Fig. 14 Safe Operating Area at  $T_c=100^\circ\text{C}$**



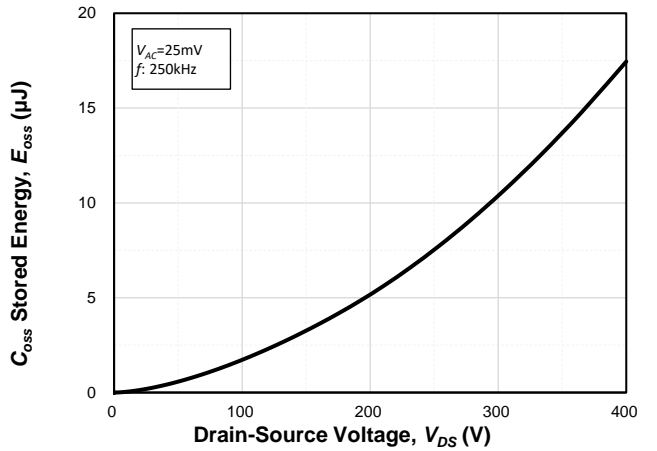
**Fig. 15 Typ. Capacitance vs.  $V_{DS}$  at  $f_{sw}=250\text{kHz}$ ,  $V_{DS}\leq 100\text{V}$**



**Fig. 16 Typ. Capacitance vs.  $V_{DS}$  at  $f_{sw}=250\text{kHz}$ ,  $V_{DS}\leq 400\text{V}$**

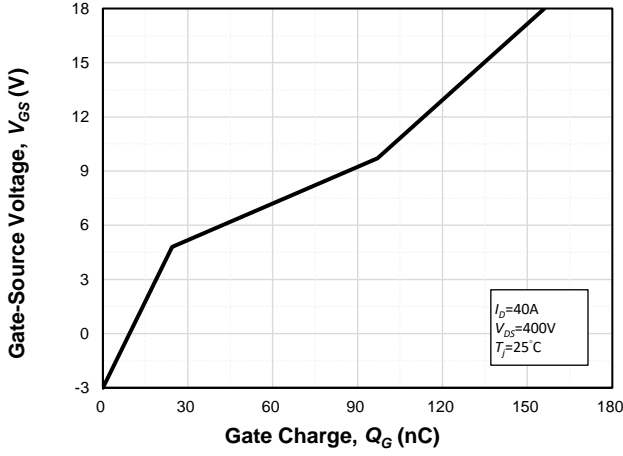


**Fig. 17 Typ. Capacitive Output Charge at  $f_{sw}=250\text{kHz}$**

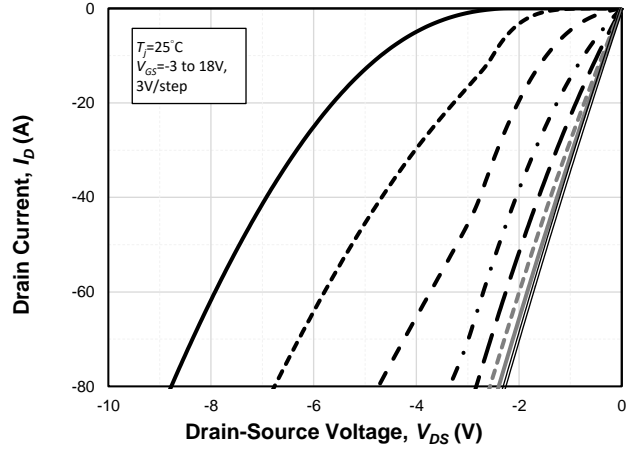


**Fig. 18 Typ.  $C_{OSS}$  Stored Energy at  $f_{sw}=250\text{kHz}$**

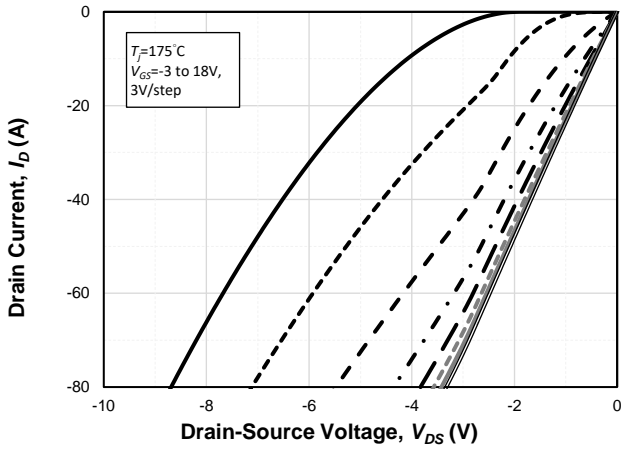
**Electrical Characteristics Diagrams**



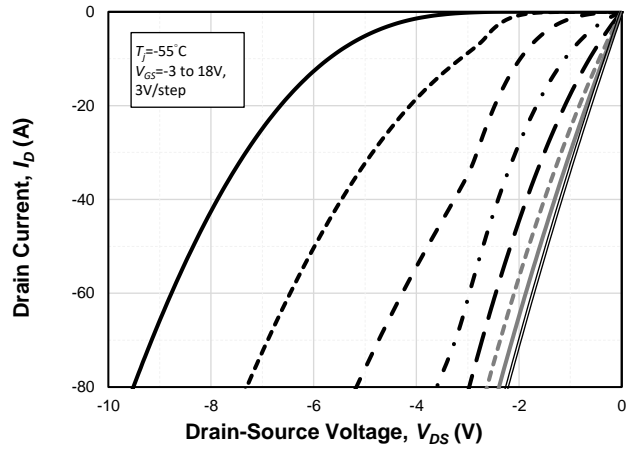
**Fig. 19 Typ. Gate Charge at  $V_{DS}=400V$ ,  $I_D=40A$**



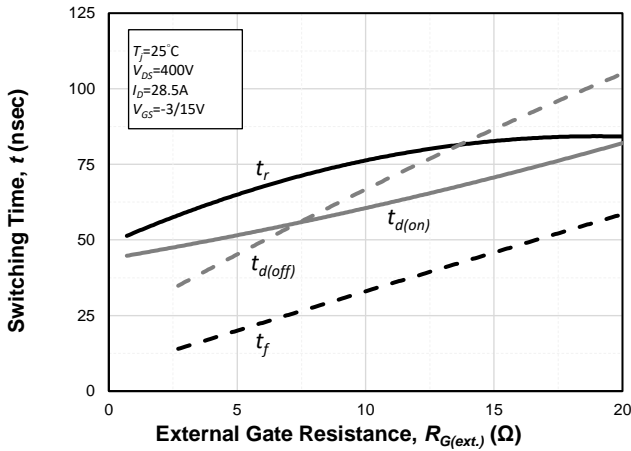
**Fig. 20 Typical Forward Characteristics of Reverse Conduction at  $T_J=25^\circ C$**



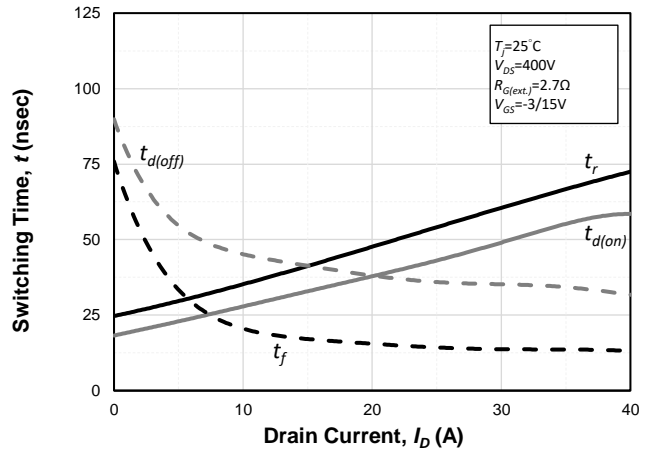
**Fig. 21 Typical Forward Characteristics of Reverse Conduction at  $T_J=175^\circ C$**



**Fig. 22 Typical Forward Characteristics of Reverse Conduction at  $T_J=-55^\circ C$**



**Fig. 23 Typ. Switching Time vs.  $R_{G(ext.)}$**



**Fig. 24 Typ. Switching Time vs.  $I_D$**

**Electrical Characteristics Diagrams**

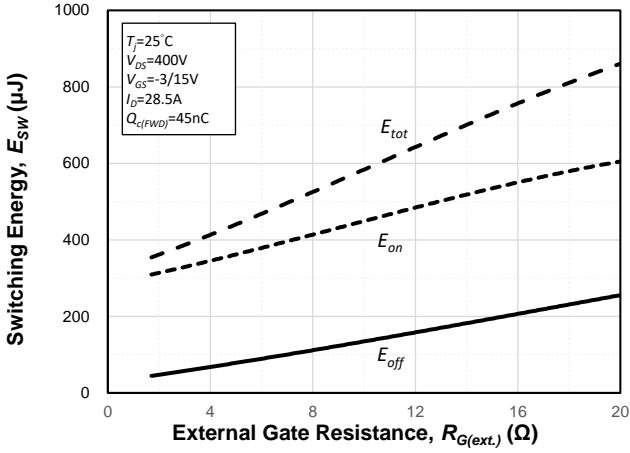


Fig. 25 Typ. Switching Energy vs.  $R_{G(ext.)}$

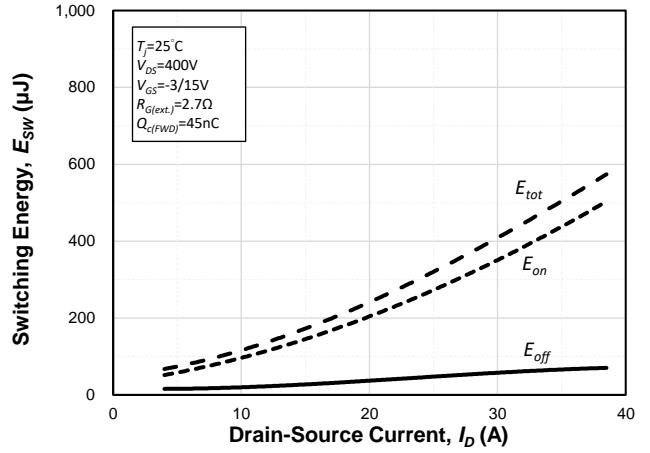
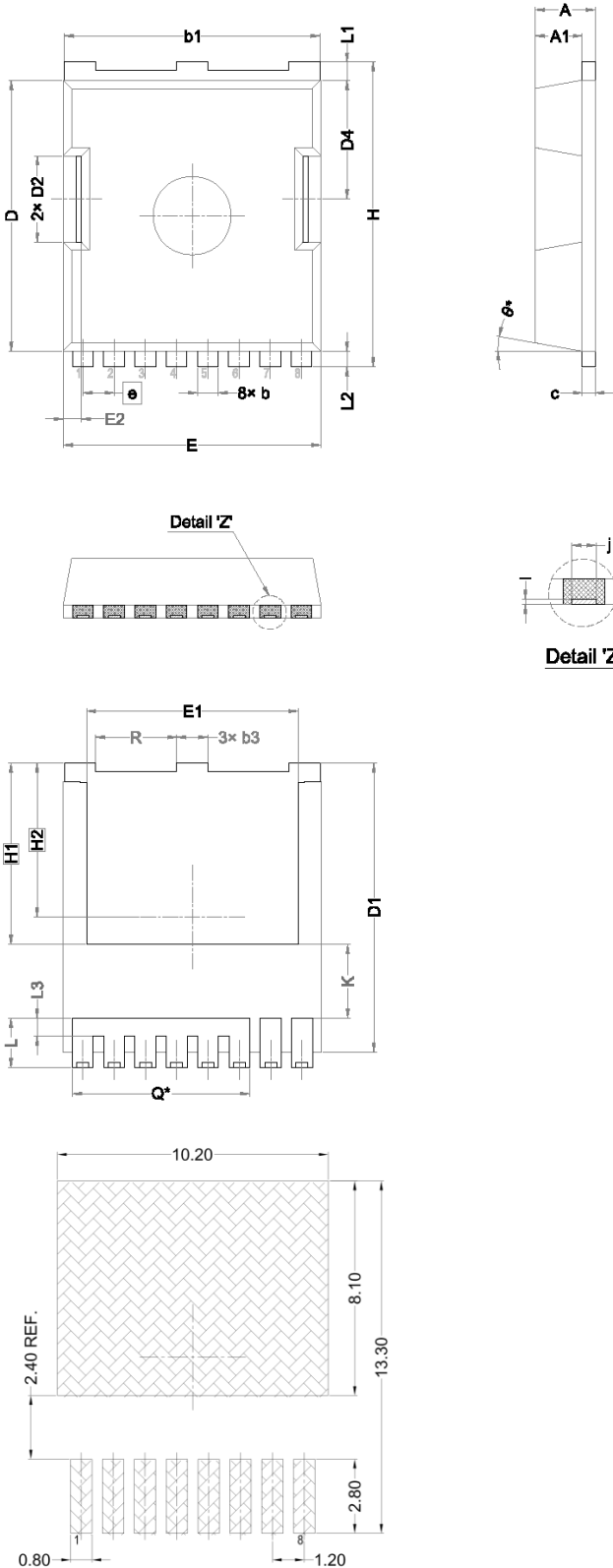


Fig. 26 Typ. Switching Energy vs.  $I_D$



**Package Outline (TOLL, MO-299B)**



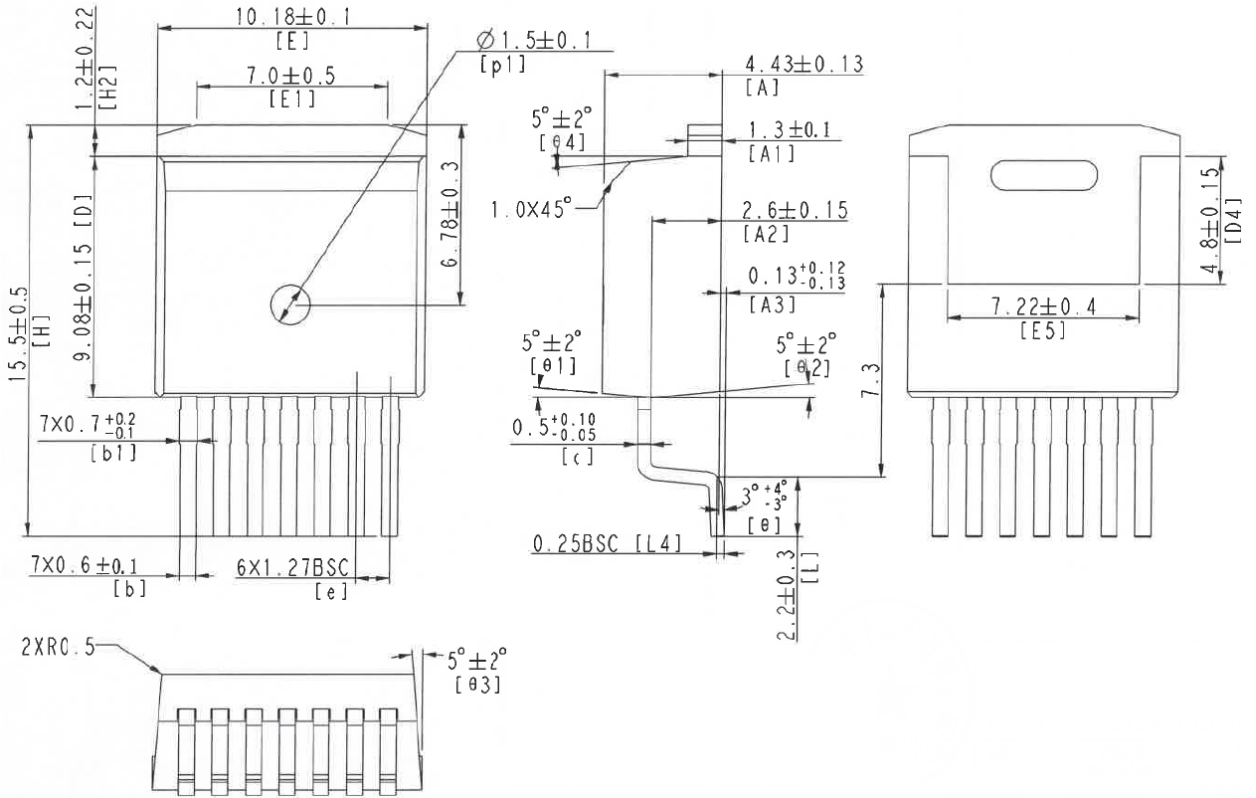
**Land Pattern (Only for reference)**

Symbol	Dimension (Millimeters)		
	Min.	Nom.	Max.
A	2.20	2.30	2.40
A1	1.70	1.80	1.90
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b3	1.10	1.20	1.30
c	0.40	0.50	0.60
D	10.28	10.38	10.48
D1	10.98	11.08	11.18
D2	3.20	3.30	3.40
D4	4.45	4.55	4.65
E	9.80	9.90	10.00
E1	8.00	8.10	8.20
E2	0.60	0.70	0.80
e	1.20 BSC.		
H	11.58	11.68	11.78
H1	6.95 BSC.		
H2	5.89 BSC.		
i	0.10 REF.		
j	0.46 REF.		
K	2.80 REF.		
L	1.40	1.90	2.10
L1	0.60	0.70	0.80
L2	0.50	0.60	0.70
L3	0.30	0.70	0.80
N	8		
Q	6.80 REF.		
R	3.00	3.10	3.20
θ	10° REF.		

**Note:**

1. Dimensions do not inclusive burrs and mold flash.
2. "\*" is for reference.

**Package Outline (TO-263-7L)**



## Revision History

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Date	Revision	Changes
23.04	Tentative	1 <sup>st</sup> issue
23.06	Preliminary	Update to preliminary version
24.04	Preliminary	Minor change
24.11	Preliminary	Update pad layout

## Important Note (Disclaimer)

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